

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination WAKABAYASHI ET AL.	
		Examiner Yogesh C. Garg	Art Unit 3625	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0105728	06-2003	Yano et al.	705/400
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP1286287 A1	02-2003	EUROPE	YANO ET AL.	G06F 17/60
	O					
	P					
	Q					
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**NON-PATENT DOCUMENTS**

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